## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | INOUE ET AL. | Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,950,716	09-1999	Appelquist et al.	165/109.1
	В	US-5,375,654	12-1994	Hougland et al.	165/109.1
	C,	US-4,554,969	11-1985	Carnavos, Theodore C.	165/154
	D	US-5,469,817	11-1995	Hoag, Kevin L.	123/41.79
	Е	US-4,194,560	03-1980	Matsuzaki, Yoshiaki	165/141
	F	US-4,924,838	05-1990	McCandless, James C.	123/541
	G	US-6,220,344	04-2001	Beykirch et al.	165/156
	Н	US-4,372,374	02-1983	Lee, Marlow	165/70
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			·

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т			:		

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	·
	w	
	x	

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.